

ES_N32WB03x Series Errata Sheet

Errata Sheet

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1. Errata List

Table 1-1 Errata Overview

Errata links		Chip version			
		Version B	Version C	Version D	
2: Bluetooth Function (BLE)	2.1: HSE as system clock	•	•	•	
	2.2: EXTI4_12 interrupts while Bluetooth protocol stack is used	•	•	•	
	2.3: LSI glitch is abnormal	•	•	/	
3: Reset and Clock Control (RCC)	3.1: Note to use of RCC_LSCTRL register	•	•	•	
	3.2: RCC_AHBRST's ADCRST bit is abnormal	•	•	•	
4: System Cache Management (CACHE)	4.1: There is abnormal fetch instruction when the bus accesses the special code logic	•	/	/	
5: Lower Power Universal Asynchronous Receiver-Transmitter (LPUART)	5.1: When LSI 32K is used as clock source, transmission at 9600 baud rate and wake-up byte are abnormal	•	•	•	
6: Serial Peripheral Interface (SPI)	6.1: SPI	6.1.1: SPI baud rate setup	•	•	•
		6.1.2: CRC calibration in slave mode	•	•	•
		6.1.2: When the Bluetooth protocol stack is used, SPI interrupts and fails to respond	•	•	•
7: I2C Bus Interface	7.1: Abnormal signal interference	•	•	•	
8: Key Scan (KEYSCAN)	8.1: When entering the Sleep mode, part of chips cannot wake up through KEYSKAN.	•	•	•	

Notes:

(1) •: problem present

(2) -: fixed

2. Bluetooth

2.1. HSE as System Clock

Description

When the Bluetooth protocol function is used, HSE 32MHz as system clock speed cannot meet the performance requirements.

Workaround

When the Bluetooth protocol function needs to be used, HSE cannot be directly used as system clock, and HSI should be selected as system clock.

2.2. EXTI4_12 interrupts while Bluetooth protocol stack is used.

Description

When the Bluetooth protocol stack function is used, the protocol will reconfigure the EXTI4_12 interrupt, which makes the configuration of EXTI4_12 interrupt during startup invalid.

Workaround

When the Bluetooth protocol stack function needs to be enabled, the protocol stack initialization will configure EXTI4_12 interrupt and use the EXTI11 interrupt function. The user needs to configure this interrupt after the protocol stack initialization and add EXTI1 clear flag byte in the interrupt processing function.

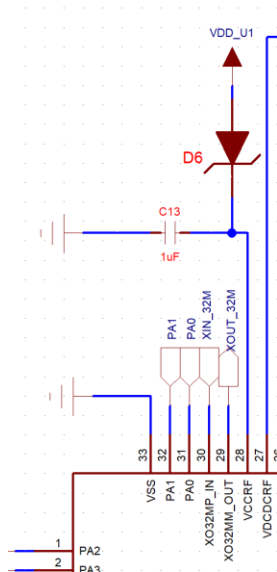
2.3. LSI issue affects wake-up.

Description

For chip version B and C, when the power supply VCCRF is over 3V, there is risk of LSI, which will lead to abnormal wake-up of the Bluetooth protocol stack.

Workaround 1

Ensure that the power supply VCCRF is lower than 3V. We recommend that VCC be connected to VCCRF after a diode to reduce the voltage, as shown in the following reference figure. The recommended diode models are BAV21W, BZT52C3V6 and BAP1321.



Workaround 2

Use LSE as low speed clock source.

Workaround 3

Use the chip of new version D.

3. Reset and Clock Control

3.1. Note to use of RCC_LSCTRL register

Description

After waking up from the Sleep mode, if we operate the register `RCC_CFG`, the register `RCC_LSCTRL` will reset to the default value.

Workaround

After waking up from the Sleep mode, first write in the register `RCC_LSCTRL`, and then operate the register `RCC_CFG`.

3.2. RCC_AHBPRST's abnormal ADCRST bit

Description

Setting the `RCC_AHBPRST` register's `ADCRST` bit cannot correctly reset the ADC module.

Workaround

When we need to reset the ADC module, manually assign default value to all ADC module registers.

4. System Cache Management (CACHE)

4.1. There is abnormal fetch instruction when the bus accesses the special code logic

Description

When chip of version B implements the special instruction sequence, there is abnormal fetch instruction, which is demonstrated by the stop of core, and then the SWD interface can access the JTAG IDCODE interface but cannot get the core ID of the chip.

Workaround

Use the chip of new version D.

5. Lower Power Universal Asynchronous Receiver-Transmitter (LPUART)

5.1. LSI 32K is used as clock source, transmission at 9600 baud rate and wake-up byte are abnormal

Description

When the LPUART uses a 32K clock source, due to the baud rate being indivisible from the clock source, there will be a baud rate deviation, leading to byte detection errors during wake up, and thus falling to wake up.

Workaround 1

When LSI needs to be used as LPUART clock source, calibrate the LSI to 32.768K for use.

Workaround 2

Use LSE as the clock source for the LPUART.

6. Serial Peripheral Interface (SPI)

6.1. SPI

6.1.1. SPI baud rate setup

Description

When in the SPI master mode and CRC calibration function are enabled, and the SPI clock frequency is above 8MHz, the CRC calibration is abnormal.

Workaround

When in the SPI master mode and CRC calibration function are enabled, the SPI clock frequency is no more than 8MHz.

6.1.2. CRC calibration in slave mode

Description

When SPI works in the slave mode and has enabled CRC calibration, even the NSS pin is of high level, if SPI receives the clock signal, it will still conduct CRC calculation.

Workaround

Before CRC calibration, clear the CRC data register first, so that the master and slave devices are synchronized in CRC calibration.

6.2. When the Bluetooth protocol stack is used, SPI1 interrupts and fails to respond.

Description

When the Bluetooth protocol stack is enabled, the ROM interrupt vector table is used, but this interrupt vector table does not map out SPI1 interrupt callback function, so it cannot be called back.

Workaround

Use DMA receiver or SPI2 module.

7. I2C Interface

7.1. Abnormal signal interference

Description

During the I2C operation process, SCL and SDA might be disturbed by glitches during communication, resulting in abnormal communication.

Workaround

Use IO software to simulate I2C.

8. Key Scan (KEYSCAN)

8.1. Retention voltage requirement for KEYSCAN in Sleep mode

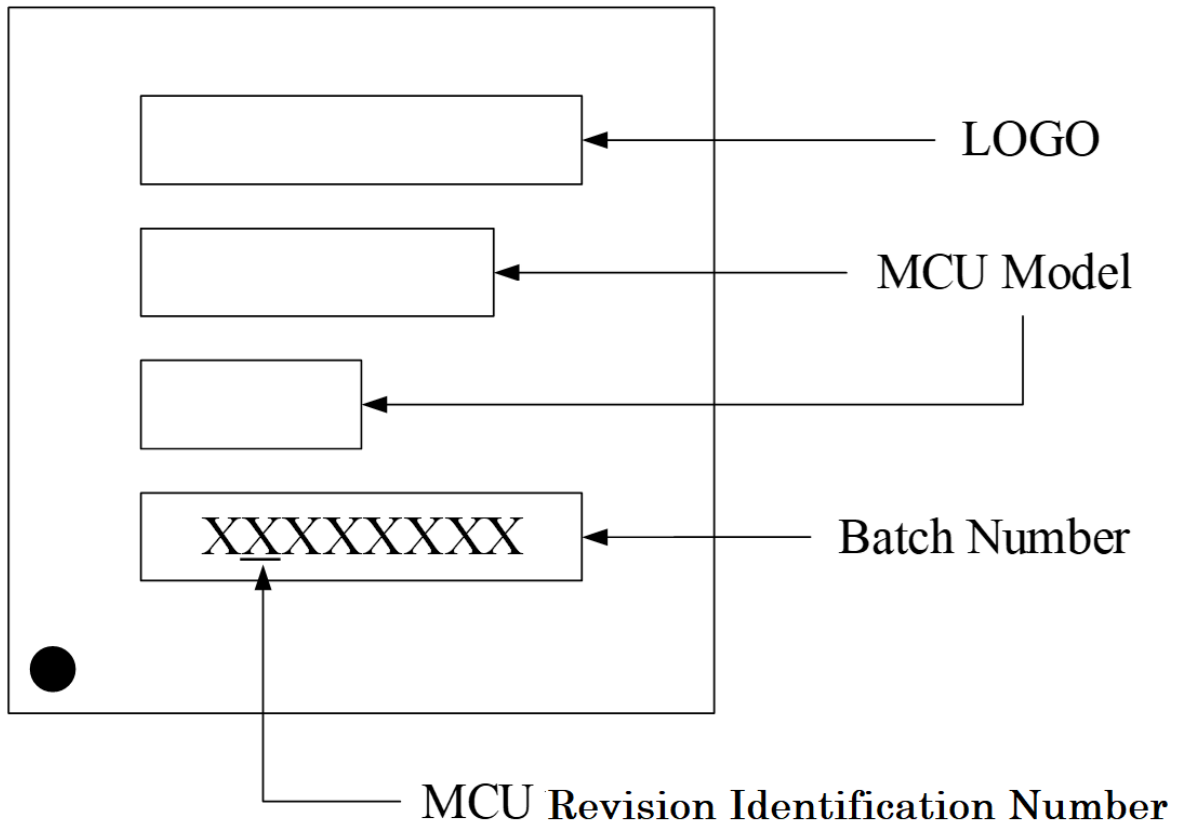
Description

Under the sleep mode, KEYSCAN requires higher retention voltage, or there might be the risks that KEYSCAN and EXT13 functions cannot wake up the chip.

Workaround

Increase the retention voltage, register configuration is `*(uint32_t*)0x40007014 = 0x00000814`. After using this configuration, the sleep power consumption increases 200nA.

9. Marking information



10. Version History

Version	Date	Changes
V1.1.0	2022.10.19	Initial release
V1.1.1	2022.03.28	Error correction

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